


<b>Search Notes</b>  	<b>Application/Control No.</b>  10587010	<b>Applicant(s)/Patent Under Reexamination</b>  KUMAKI ET AL.
	<b>Examiner</b>  Dawn Garrett	<b>Art Unit</b>  1786

SEARCHED			
Class	Subclass	Date	Examiner
	see EAST search printout		

SEARCH NOTES		
Search Notes	Date	Examiner
EIC-1700 STIC structure search (see attached printout)	2/26/2009	D. Garrett
Inventor name search	12/19/2009	D. Garrett
EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	12/19/2009 and 12/20/2009	D. Garrett
updated EAST search (see printout); Databases: JPO, EPO, DERWENT, USPAT, USPGPUB	6/16/2010	D. Garrett

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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